

ABSTRACT:

Digital circuitry is tested through effecting a paired data loop-back from a first buffered output to a first buffered input whilst within the circuitry executing at least part of the test through using a **Built-In-Self-Test** methodology. In particular, the loop-back is effected from the first buffered data output to a buffered control input, from a buffered control output to the first buffered data input, or both. Advantageously, the buffering is associated to executing a conversion between a digital full swing internal signal and an analog low swing external signal with respect to core circuitry of the digital circuitry.

Figure 4

